



Standard Test Method for Monitoring of Atmospheric Corrosion Chambers by Quartz Crystal Microbalances¹

This standard is issued under the fixed designation B808; the number immediately following the designation indicates the year of original adoption or, in the case of revision, the year of last revision. A number in parentheses indicates the year of last reapproval. A superscript epsilon (ϵ) indicates an editorial change since the last revision or reapproval.

1. Scope

1.1 This test method monitors the reactivity of a gaseous test environment in which metal surfaces (for example, electrical contacts, assembled printed wiring boards, and so forth) and other materials subject to pollutant gas attack undergo accelerated atmospheric corrosion testing. This test method is applicable to the growth of adherent corrosion films whose total corrosion film thickness ranges from a few atomic monolayers to approximately a micrometre.

1.2 The test method provides a dynamic, continuous, in-situ, procedure for monitoring the corrosion rate in corrosion chambers; the uniformity of corrosion chambers; and the corrosion rate on different surfaces. Response time in the order of seconds is possible.

1.3 With the proper samples, the quartz crystal microbalance (QCM) test method can also be used to monitor the weight loss from a surface as a result of the desorption of surface species (that is, reduction of an oxide in a reducing atmosphere). (Alternative names for QCM are quartz crystal oscillator, piezoelectric crystal oscillator, or thin-film evaporation monitor.)

1.4 This test method is not sufficient to specify the corrosion process that may be occurring in a chamber, since a variety of pollutant gases and environments may cause similar weight gains.

1.5 This test method is generally not applicable to test environments in which solid or liquid particles are deposited on the surface of the quartz crystal.

1.6 The values stated in SI units are to be regarded as standard. The values in parentheses are for information only.

1.7 *This standard does not purport to address all of the safety concerns, if any, associated with its use. It is the responsibility of the user of this standard to become familiar with all hazards including those identified in the appropriate*

Safety Data Sheet (SDS) for this product/material as provided by the manufacturer, to establish appropriate safety and health practices, and determine the applicability of regulatory limitations prior to use.

2. Referenced Documents

2.1 *ASTM Standards:*²

B810 Test Method for Calibration of Atmospheric Corrosion Test Chambers by Change in Mass of Copper Coupons

3. Summary of Test Method

3.1 A single crystal of quartz has various natural resonant frequencies depending on the crystal's size and shape. The decrease in natural frequency is linearly proportional to the crystal mass and the mass of well-bonded surface films. For crystals with reactive metal films on the surface (usually driving electrodes), the mass of the crystal/metal film increases as the metal oxidizes or forms other compounds with gases adsorbed from the atmosphere.^{3,4} Thus, by measuring the rate of resonant frequency change, a rate of corrosion is measured. Non-adherent corrosion films, particles, and droplets yield ambiguous results. A review of theory and applications is given in Lu and Czanderna.⁵ See **Appendix X1** for discussion of the quantitative relationship between frequency change and mass change.

3.2 The chamber environmental uniformity and corrosion rate can be measured by placing matching quartz crystals with matching reactive metal films at various locations in the chamber. If the chamber and corrosion rate have been standardized, the corrosion rate on various surface materials that have been deposited on the quartz crystal can be determined.

² For referenced ASTM standards, visit the ASTM website, www.astm.org, or contact ASTM Customer Service at service@astm.org. For *Annual Book of ASTM Standards* volume information, refer to the standard's Document Summary page on the ASTM website.

³ King, W. H. Jr., *Analytical Chemistry*, Vol 36, 1964, p. 173.

⁴ Karmarkar, K. H. and Guilbaut, G. G., *Analytical Chemistry Acta*, Vol 75, 1975, p. 111.

⁵ Lu, C. and Czanderna, A. W. Eds., *Applications of Piezoelectric Quartz Crystal Microbalances*, Elsevier, c1984.

¹ This test method is under the jurisdiction of ASTM Committee B02 on Nonferrous Metals and Alloys and is the direct responsibility of Subcommittee B02.11 on Electrical Contact Test Methods.

Current edition approved Oct. 1, 2015. Published October 2015. Originally approved in 1997. Last previous edition approved in 2010 as B808 – 10. DOI: 10.1520/B0808-10R15.

4. Significance and Use

4.1 Corrosion film growth with thicknesses varying from a monolayer of atoms up to 1 μm can readily be measured on a continuous, real-time, in-situ, basis with QCMs.

4.2 The test results obtained for this test method are influenced by various factors, including geometrical effects, temperature, humidity, film thickness, film materials, electrode conditions, gases in the corrosion chamber, atmospheric pressure, and so forth. Calibration of coated crystals and instrumentation and reproducible crystal operating conditions are necessary for consistent results.

5. Apparatus

5.1 Apparatus can be a simple series circuit of crystal (with electrodes and sensing film), oscillator (typically 6 MHz) and frequency counter (± 10 -Hz accuracy and stability), as schematically shown in Fig. 1.

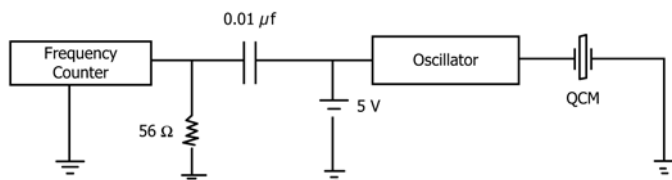


FIG. 1 Schematic of QCM and Related Electronics

5.2 *Commercial, Thin-Film Monitors*,⁶ incorporating those functions that read out thicknesses or weight gain are also available and acceptable after they have been calibrated.

5.3 *Microbalance*, with an accuracy of $\pm 2 \mu\text{g}$ is needed for calibration procedures.

5.4 *Recording Devices or Computers* are needed for real-time, continuous measurements.⁷

6. Materials

6.1 Crystals shall be of the AT⁵ cut variety with a resonant frequency in the MHz range and matched to the frequency measuring apparatus used. Quartz crystal surfaces shall be polished to a surface finish with an arithmetical mean deviation, R_a , of less than 0.1 μm . With this surface finish, the crystal appears optically transparent to the human eye.⁸

6.2 Electrodes, used to drive the crystal's resonant frequency, can be made from any electrically conducting material and usually are a metal film evaporated on the quartz crystal surface. The material under study or being used to calibrate the system may be the same as or different than the electrode material. If the two materials are different, the potential corrosion of the electrodes shall be accounted for during the design and subsequent experiments. Depending on the materials under test, the QCMs can have copper, silver,

nickel, zinc, gold, etc. electrodes. The preferred method of deposition is by evaporation for a high purity, smooth surface. If sublayers are used to enhance the adhesion of the final electrode, they should be covered by the final electrode material so that less than 1 % of the metallic area is of exposed sublayer material. Because of the fragility of the metal electrode there should be multiple (three or more), spring-loaded contacts between the crystal and electronics.

6.3 After metallization of the crystals, they should be stored in desiccators. After two years storage or if the metallization shows discoloration or staining, the crystals shall be discarded. Crystal surfaces should not be chemically or mechanically cleaned before use in the corrosion chamber. They should be blown clean with inert compressed gas. Chilling and condensation on the surface, as can occur with the use of pressurized fluorocarbons, shall be avoided. Care shall be exercised so that the crystals are only handled by clean tweezers or tongs and never touched by hands.

7. Calibration

7.1 QCMs and its electronics shall be calibrated initially in a given corrosion system and thereafter on an annual basis. Calibration shall be performed with the same shape and size of crystal holder to be used during operation. Recalibration shall be performed if the crystal holder geometry is changed. Calibration can be done by comparison to a standard such as actual gravimetric weighing on a microbalance ($\pm 2 \mu\text{g}$). Use a sample of the same material as the sensing film with a minimum area of 5 cm^2 and a thickness of 0.1 to 0.6 mm (see Test Method B810). Foil surface roughness should be within ± 20 % of the QCM sensing film roughness. The procedure for the generation (that is, evaporation) and cleaning of the gravimetric sample should be the same as used for the sensing films. The age and storage of the gravimetric sample should be comparable to the age of the QCM sensing film. Allow the foil to equilibrate with the microbalance atmosphere for 0.5 h, then weigh the sample with ± 2 - μg accuracy before exposure. Suspend the weighed gravimetric sample between two similarly treated QCMs spaced 20 cm apart with the large surface area dimension of the samples parallel to the air flow. After sufficient exposure, as determined in the paragraph below, remove the sample from the corrosion chamber, equilibrate it with the balance atmosphere, and reweigh. The gravimetrically measured, foil weight gain per unit area should be within ± 10 % of the calculated weight gain, found on the active area of the QCM.

7.2 A weight gain of the metal foil of 50 μg is sufficient for a microbalance with ± 2 - μg reproducibility and is sufficient for calibration. (If the reproducibility of the microbalance is poorer than $\pm 2 \mu\text{g}$, proportionally greater weight gain shall be used.) If the sensing material was copper and the corrosion film was Cu_2O , 50 $\mu\text{g}/5 \text{ cm}^2$ would correspond to a film thickness of 149 nm if the density of Cu_2O was 6 g/cm^3 and the percentage of oxygen in the film was 11 % (16/143). For improved accuracy, greater weight gain may be used. However, the calculated thickness of the corrosion film should not exceed 50 % of the electrode thickness.

⁶ Instruments of this type are used in semiconductor manufacture and may be found by searching for deposition thickness monitors.

⁷ Schubert, R. "A Second Generation Accelerated Atmospheric Corrosion Chamber," *ASTM STP 965*, 1988, p. 374.

⁸ Most instrument suppliers of thin film monitors also sell crystals with various coatings and roughness.